

## Si doped highly crystal mesoporous $\text{In}_2\text{O}_3$ nanowires: synthesis, characterization and ultra-high response to $\text{NO}_x$ at room temperature

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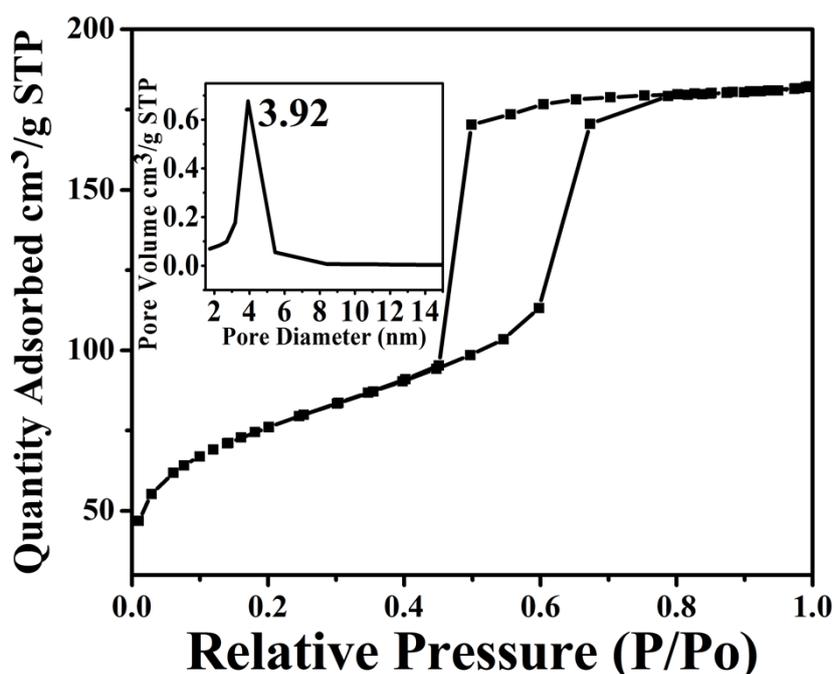


Fig. S1. BET specific surface areas of SBA-16 (BET: 270.99 m<sup>2</sup>/g; the pore size is 3.92nm).

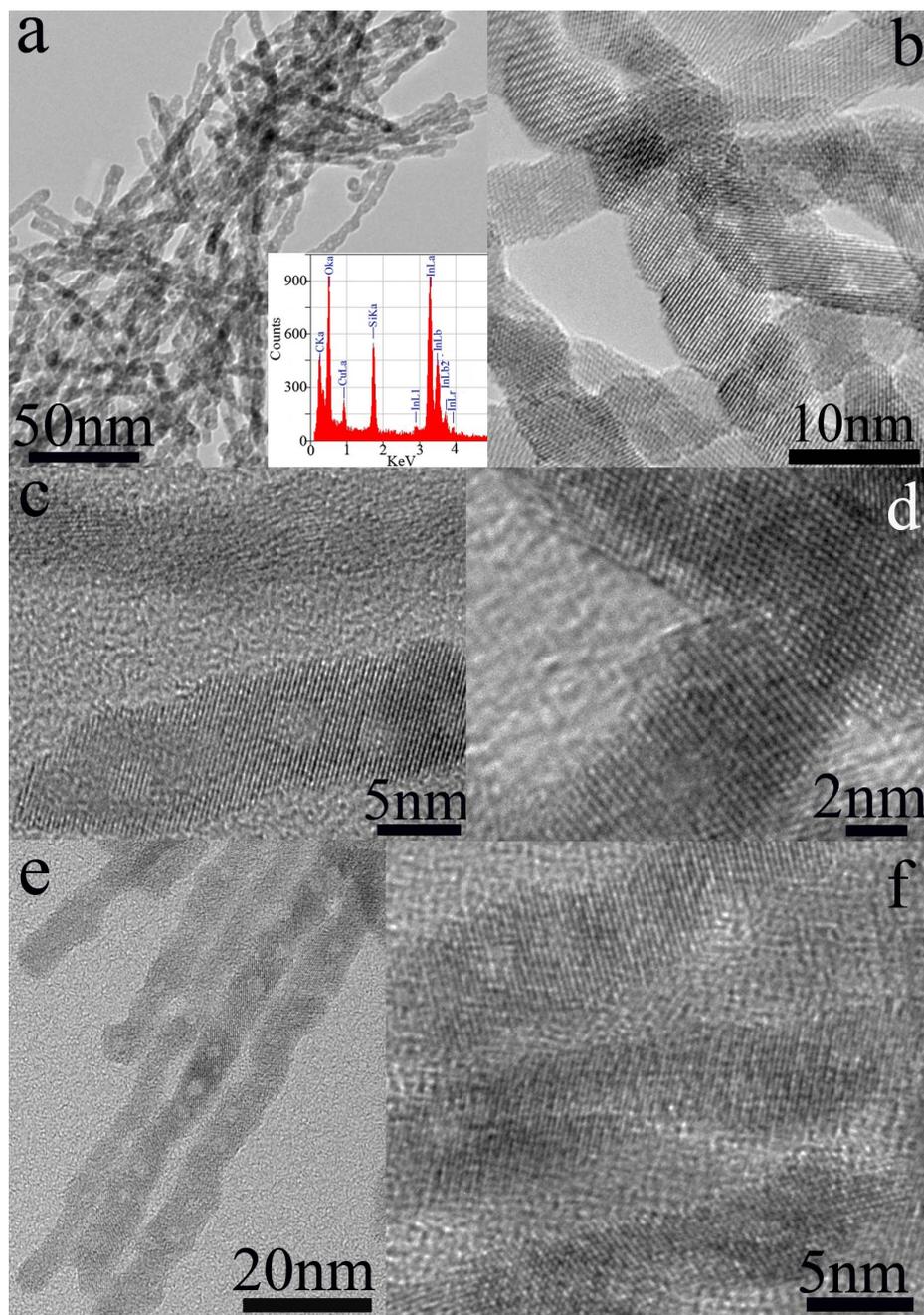


Fig. S2. TEM/HRTEM images of  $\text{In}_2\text{O}_3$  NWs doped by amorphous silica samples.

(a)~(f) INW-2, and (f) is the HRTEM image of Fig.3e.

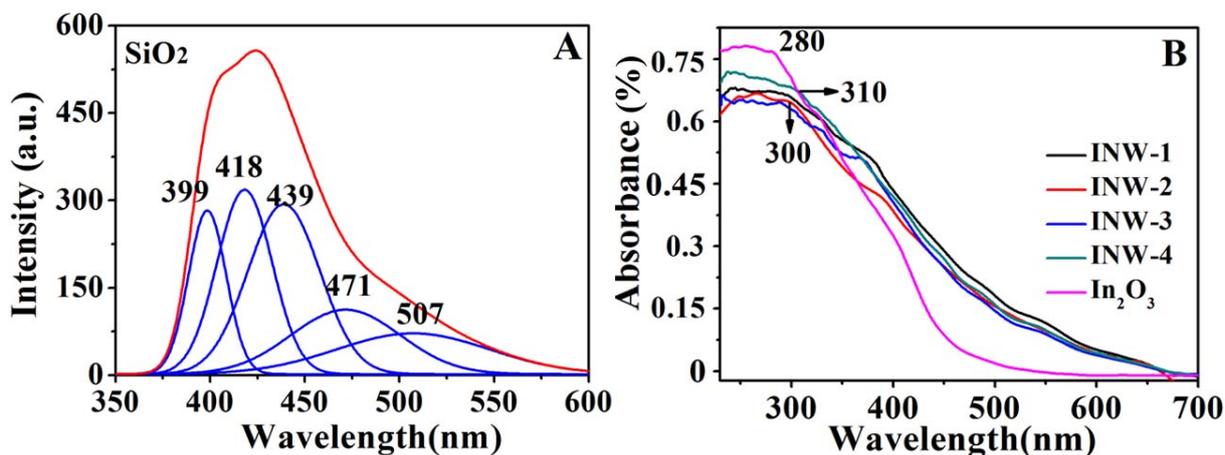


Fig. S3. PL spectra of (A) SiO<sub>2</sub> (SBA-16) with 325 nm excitation at room temperature of and (B) UV-vis diffuse absorption spectra of SiO<sub>2</sub>-In<sub>2</sub>O<sub>3</sub> composites with different atomic ratios.

Fig.S3A is PL spectra of SiO<sub>2</sub> (SBA-16) with 325 nm excitation at room temperature. In Figure.S3B, the absorption edge around 550 nm was pure In<sub>2</sub>O<sub>3</sub> NWs. The absorption edges observed to be around 675 nm were In<sub>2</sub>O<sub>3</sub> NWs doped by amorphous silica samples (INW-1, INW-2, INW-3 and INW-4). Besides, it was denoted that the absorption in UV light region decreased for pure In<sub>2</sub>O<sub>3</sub> NWs compared with In<sub>2</sub>O<sub>3</sub> NWs doped by amorphous silica. This demonstrated that the coverage of SiO<sub>2</sub> on In<sub>2</sub>O<sub>3</sub> surface did not restrain the absorption of UV light. This was different from previous studies<sup>1</sup> about the SiO<sub>2</sub>-coated TiO<sub>2</sub> (the average thickness of SiO<sub>2</sub> coating layer was 2-3 nm).

Furthermore, In<sub>2</sub>O<sub>3</sub> NWs doped by amorphous silica samples (HCMIA) with a high aspect ratio and peculiar morphologies should favor the existence of large quantities of oxygen vacancies, which would induce the formation of new energy levels in the band gap. The UV absorption of HCMIA occurred at 300-310 nm indicating that the existence of weak quantum confinement effect<sup>2</sup>.

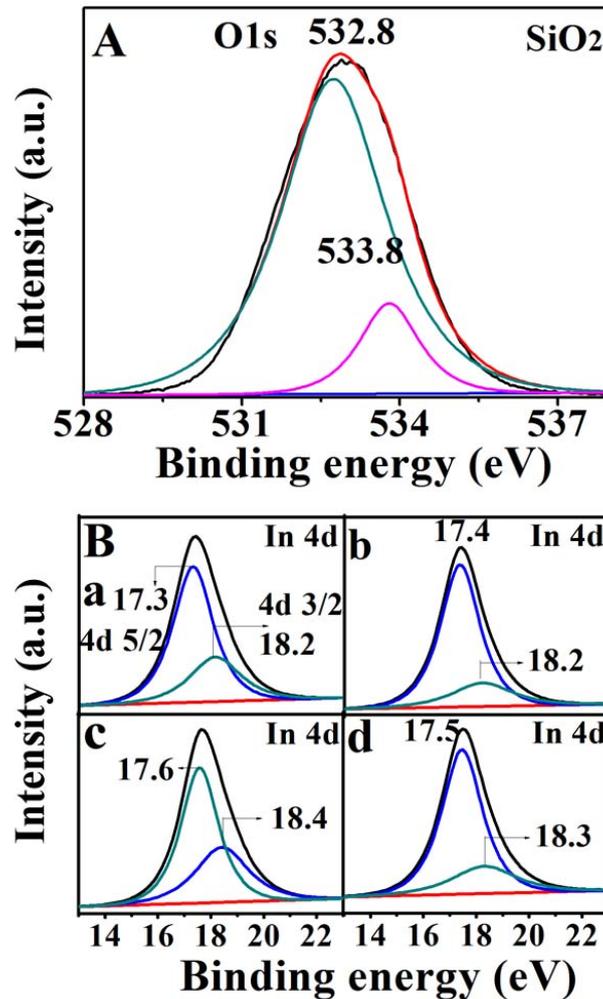


Fig. S4. XPS spectra of (A) O1s of SiO<sub>2</sub> (SBA-16) and (B) low binding energy region in XPS of samples containing valence band in In4d (a) In<sub>2</sub>O<sub>3</sub>, (b) INW-1, (c) INW-2 and (d) INW-4, respectively.

Fig. S4A showed the O1s spectra of pure SiO<sub>2</sub> (SBA-16) located at 532.8 eV were essentially composed one of a major component, which could be attributed to Si-O binding energy<sup>3</sup>. The spectra depicted a secondary component, which located at higher energy (533.8 eV) and could be ascribed to O-H groups linked to Si cations.

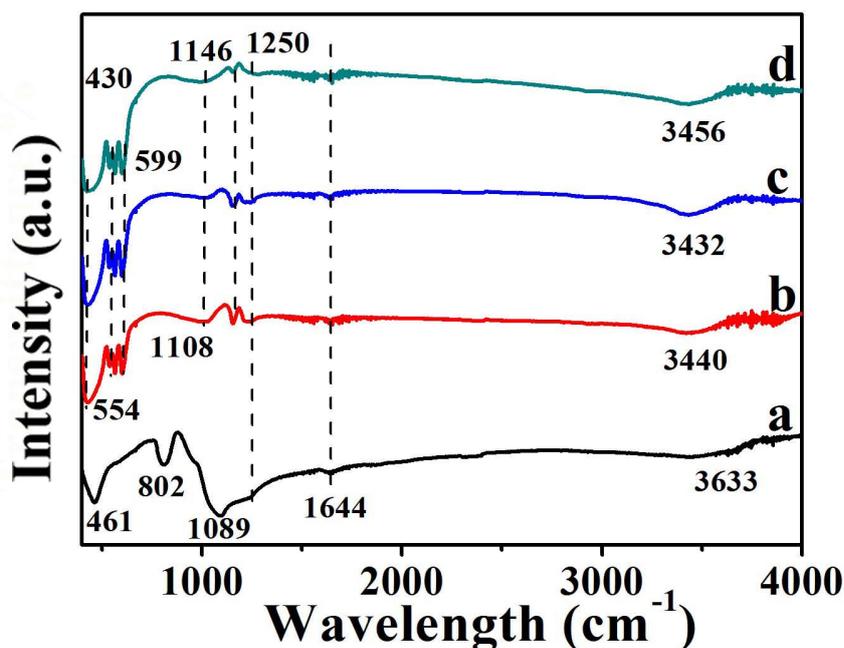


Fig. S5 FT-IR spectra of (a) SiO<sub>2</sub>, (b) INW-1, (c) INW-2 and (d) INW-4, respectively.

FT-IR spectra of SiO<sub>2</sub>, INW-1, INW-2 and INW-4 samples were shown in Fig. S5. As shown in Fig. S5, there were adsorptive peaks of amorphous silica hydroxyl at 3432-3633 cm<sup>-1</sup> and the spectrum should be attributed to the stretching of hydrogen (-OH) bond of H<sub>2</sub>O<sup>4</sup>. The spectra of INW-1 and INW-2 appeared blue shifted to 3432 cm<sup>-1</sup>, and red shifted in INW-4. Moreover, the peak appeared at 1644 cm<sup>-1</sup> and 461 cm<sup>-1</sup> were assigned to the bending vibrations of (-OH) bond and Si-O group<sup>5</sup> respectively. Furthermore, 1089 cm<sup>-1</sup> was symmetric stretching of Si-O-Si group whereas 802 cm<sup>-1</sup> was asymmetric stretching of Si-O-Si group. According to previous studies<sup>6-7</sup>, the band centered at 1108 cm<sup>-1</sup> was assigned to the stretching vibration of Si-O-metal<sup>5</sup>, that was Si-O-In stretching vibration. 500 cm<sup>-1</sup> absorption could be attributed to the vibrations of In-O bond<sup>6</sup>. So, the absorptions in 554 cm<sup>-1</sup> and 599 cm<sup>-1</sup> and 430 cm<sup>-1</sup> were assigned to the stretching vibration of In-O<sup>7-9</sup>, respectively. In-O bond in plane bending vibrations should be appeared at 410 cm<sup>-1</sup>. Comparing with the references, the adsorptive peaks shifted in Fig. S 5(b-d) might be affected by Si-O-In.

Tab. S1 Comparison of the response-recovery results of (A) response and (B) response time of mesoporous INW composited NFs thin film sensor with different atomic ratios to NO<sub>x</sub> (RH: 42 %)

Volume concentration (ppm)		97.0	48.5	<b>29.1</b>	<b>9.70</b>	4.85	2.91	0.97
INW-1	Response	39.56	40.42	53.33	23.16	4.63	4.06	-
	Response time/s	196	292.7	295.3	308	48	60.7	-
INW-2	Response	115.6	94.7	<b>41.64</b>	<b>39.18</b>	30.62	9.54	1.68
	Response time/s	118	109	108	151	330.7	309.3	194.7
INW-3	Response	17.39	13.6	7.07	2.8	-	-	-
	Response time/s	18	70	127	103	-	-	-
INW-4	Response	1.43	1.81	1.15	1.51	-	-	-
	Response time/s	64	92	133.5	63	-	-	-

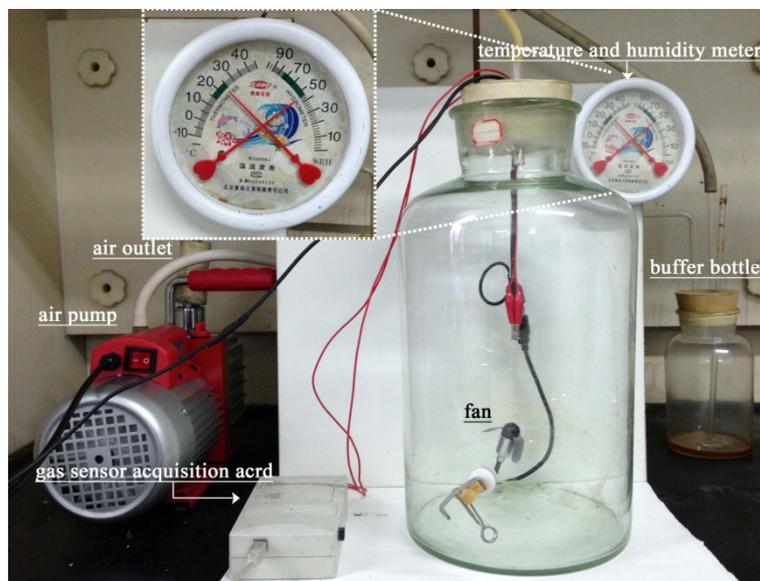


Fig. S6 Images of the gas sensing test device

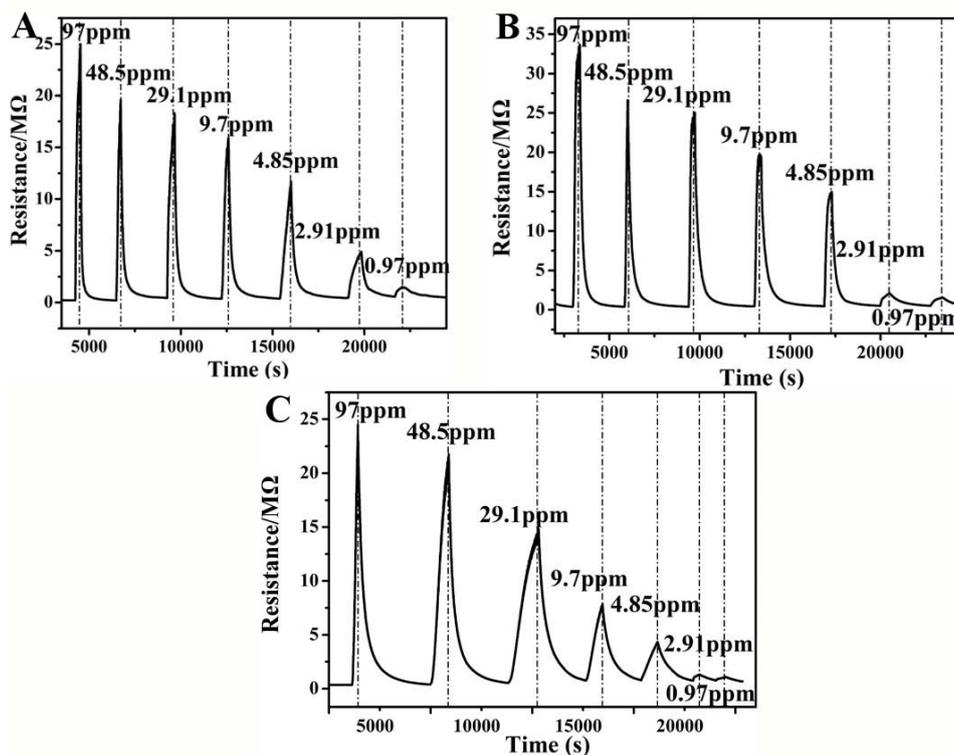


Fig S7. Response-recovery curves of the INW-2 sensor to 97ppm-0.97ppm at room temperature in the different RH (A) 42%, (B) 61% and (C) 80%.

Tab.S2 The gas response of the INW-2 sensor to 97ppm-0.97ppm NO<sub>x</sub> at room temperature, the RH range of 42-80%.

C/ppm	97.0	48.5	29.1	9.7	4.85	2.91	0.97
Gas Reponse at 42% RH	115.6	94.7	41.64	39.18	30.62	9.54	1.68
Gas Reponse at 61% RH	110.8	90.6	38.7	35.1	30.7	8.48	1.39
Gas Reponse at 80% RH	93.7	85/4	35.5	31.6	28.6	4.41	0.77

**Table S3.** The gas sensing properties of similar detection methods

Metal Oxide	Optimal Mixing ratio	Morphology	Optimal Temperature (°C)	Response/ppm		Reference
				S	C	
In <sub>2</sub> O <sub>3</sub>	Ta (2.3at. %)	Film	400	3.81	0.08	Chem.Mater, 24(2012), 2864-2871
In <sub>2</sub> O <sub>3</sub>	SnO <sub>2</sub> (0.1 mol%)	Powders	250	2906	10	Sens. Actuators, B. 151(2010),265-273
In <sub>2</sub> O <sub>3</sub>	-	Nanosheet	250	164	50	Sens. Actuators, B. 208(2015),436-443
Fe-In <sub>2</sub> O <sub>3</sub>	Fe (0.05wt. %)	Powders	100	117	1	Sens. Actuators, B. 191(2014),806-812
In <sub>2</sub> O <sub>3</sub>	-	Microsphere	200	10	1	Sens. Actuators, B. 187(2013),495-502
In <sub>2</sub> O <sub>3</sub>	-	Particles	275	8	1	Electron.Mater.Lett. 10(2014),509-513
In <sub>2</sub> O <sub>3</sub> /rGO	GO (0.5wt. %)	Composites	RT	0.25	1	Acs Appl.Mater.Interfaces. 6(2014),21093-21100
In <sub>2</sub> O <sub>3</sub>	-	Nanowire	150	50	10	Appl.Phys.A 85(2006),241-246
Zn- In <sub>2</sub> O <sub>3</sub>	In:Zn (7:1)	Flower-like	300	27.4	5	Rsc.Adv., 4(2014),15161-15170
In <sub>2</sub> O <sub>3</sub>	-	Microsphere	80	323.5	0.5	Rsc.Adv., 5(2015),4609-4614
In <sub>2</sub> O <sub>3</sub>	-	Nanoplates	150	73	1	Rsc.Adv., 4(2014),4831-4835
In <sub>2</sub> O <sub>3</sub>	-	Mesoporous	100	37.8	5	Sens. Actuators, B. 187(2013),484-494
In <sub>2</sub> O <sub>3</sub>	-	Slice-like	250	1.5	5	Sens. Actuators, B. 176(2013),258-263

## References

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